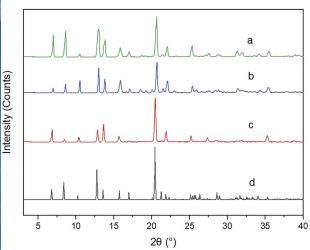
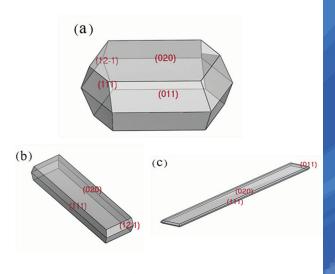
Powder Diffraction PDJ Journal of Materials Characterization

Predicting Crystal Morphology of Venlafaxine Hydrochloride



PXRD patterns of precipitates from three solvents (a)–(c) and the calculated pattern (d) that is without preferred orientation.



Predicted crystal morphologies for each of the three precipitates

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Aims & Scope

ICDD's quarterly, and special topical issue, international journal, *Powder Diffraction*, focuses on materials characterization employing X-ray powder diffraction and related techniques. With feature articles covering a wide range of applications, from mineral analysis to epitactic growth of thin films to advances in application software and hardware, this journal offers a wide range of practical applications. ICDD, in collaboration with the Denver X-ray Conference Organizing Committee, has increased services for the subscribers of Powder Diffraction and authors of Advances in X-ray Analysis. Beginning in 2006, ICDD offered a copy of the previous year's edition of AXA to Powder Diffraction institutional subscribers who receive both print and on-line versions. This effectively doubles the number of articles annually available to Powder Diffraction subscribers and significantly increases the circulation for the authors in Advances in X-ray Analysis.

Subject coverage includes:

- Techniques and procedures in X-ray powder diffractometry
- Advances in instrumentation
- Study of materials including organic materials, minerals, metals and thin film superconductors
- Publication of powder data on new materials

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The International Centre for Diffraction Data ($ICDD^{(R)}$) is a non-profit scientific organization dedicated to collecting, editing, publishing, and distributing powder diffraction data for the identification of materials. The membership of the ICDD consists of worldwide representation from academe, government, and industry.

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EDITORIAL

Camden R. Hubbard	Recent readership and impact metrics for the Journal <i>Powder Diffraction</i> (PDJ) doi:10.1017/S0885715622000306	121		
TECHNICAL ARTICLES				
Winnie Wong-Ng, Yuqi Yang, YuCheng Lan, Guangyao Liu, Amrit Kafle, Weifang Liu, Jie Hou, Donald Windover, Qing Huang, Sergiy Krylyuk and James A. Kaduk	Powder X-ray structural analysis and bandgap measurements for $(Ca_xSr_{2-x})MnWO_6$ (<i>x</i> = 0.25, 0.5, 0.75, 1.5, 1.75) doi:10.1017/S0885715622000185	122		
Chenjing Liang, Jianghai Zhuang, Chenghan Zhuang, Zhaoxia Zhang, Guanglie Lv and Guoqing Zhang	Crystal morphology prediction and experimental verification of venlafaxine hydrochloride doi:10.1017/S0885715622000264	133		

NEW DIFFRACTION DATA

James A. Kaduk, Stacy Gates-Rector, Amy M. Gindhart and Thomas N. Blanton	Crystal structure of merimepodib, $C_{23}H_{24}N_4O_6$ doi:10.1017/S0885715622000148	143
Yewon Lee, Yulong Wang, Peter G. Khalifah, Peter W. Stephens, James A. Kaduk, Stacy Gates-Rector, Amy M. Gindhart and Thomas N. Blanton	Crystal structure of baricitinib, C ₁₆ H ₁₇ N ₇ O ₂ S doi:10.1017/S088571562200015X	150
James A. Kaduk, Nicholas C. Boaz, Stacy D. Gates-Rector, Amy M. Gindhart and Thomas N. Blanton	Crystal structure of fulvestrant hydrate (ethyl acetate), $C_{32}H_{47}F_5O_3S$ (H ₂ O) _{0.16} (C ₄ H ₈ O ₂) _{0.025} doi:10.1017/S0885715622000239	157
Dier Shi, Jiyong Liu and Xiurong Hu	Crystal structure and X-ray powder diffraction data for two solid-state forms of topiroxostat doi:10.1017/S088571562200029X	166
James A. Kaduk	Crystal structure of alfuzosin hydrochloride, $C_{19}H_{28}N_5O_4Cl$ doi:10.1017/S0885715622000288	171

INTERNATIONAL REPORT

Susan A. Bourne	ePCCr: an online conference organized jointly with the African Light Source and the	183
	African Physical Society	
	doi:10.1017/S0885715622000276	

CALENDARS OF MEETINGS, SHORT COURSES AND WORKSHOPS

Gang Wang	Calendar of forthcoming meetings doi:10.1017/S0885715622000318	187
Gang Wang	Calendar of short courses and workshops doi:10.1017/S088571562200032X	188

On the Cover: In the manuscript "Crystal Morphology Prediction and Experimental Verification of Venlafaxine Hydrochloride" by C. Liang, *et al*, it was shown that modeling can be successfully used to predict the influence of solvent effects on crystal habit of venlafaxine hydrochloride. Modeling of habit of the precipitates was based on the modified attachment energy model using molecular dynamics simulation and was supported by showing the differences in the X-ray powder diffraction patterns of the three precipitates compared with the calculated pattern. Further, physical properties of the precipitates from the three solvents were shown to be related with the morphologies of the crystals.

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Rietveld Refinement & Indexing Clinic:

Powder pattern indexing and Rietveld structural refinement techniques are complementary and are often combined to determine the structure of a material. Successful indexing of a powder pattern is considered strong evidence for phase purity. Indexing is considered a prelude to determining the crystal structure, and permits phase identification by lattice matching techniques. This clinic introduces the theory and formalisms of various indexing methods and structural refinement techniques along with quantitative analysis. One unique aspect of this clinic is the extensive use of computer laboratory problem solving and exercises that teach method development in a hands-on environment.

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More information at www.icdd.com/icdd-education

Please note: A minimum of 10 registrants per course is required, otherwise the course will be cancelled and your registration fee will be refunded. You will be notified of a course cancellation no later than two weeks prior to the start of the course.



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Eileen Jennings, Education Coordinator Tel: 610.325.9814 Fax: 610.325.9823 Email: clinics@icdd.com

Location

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Does your research project involve the preparation and characterization of new materials using powder diffraction techniques?

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Please email sample patterns to:

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